

Resource Summary Report

Generated by [NIF](#) on Sep 12, 2026

FEI: Metrios TEM for Semiconductors

RRID:SCR_019893

Type: Tool

Proper Citation

FEI: Metrios TEM for Semiconductors (RRID:SCR_019893)

Resource Information

URL: <https://www.fei.com/products/tem/metrios-for-semiconductors/>

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Description: Transmission electron microscope that provides fast, precise measurements for semiconductor manufacturers to develop and control their wafer fabrication processes.

Resource Type: instrument resource

Keywords: FEI, TEM, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Metrios TEM for Semiconductors

Resource ID: SCR_019893

Alternate IDs: Model_Number_Metrios

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260912T195924+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Metrios TEM for Semiconductors.

No alerts have been found for FEI: Metrios TEM for Semiconductors.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.